

Application/Control No.	Applicant(s)/Patent under Reexamination
10/707,106	CHANG ET AL.
Examiner	Art Unit
Than Nguyen	2187

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
West		1  2(06	N:-V
			<u> </u>
·			